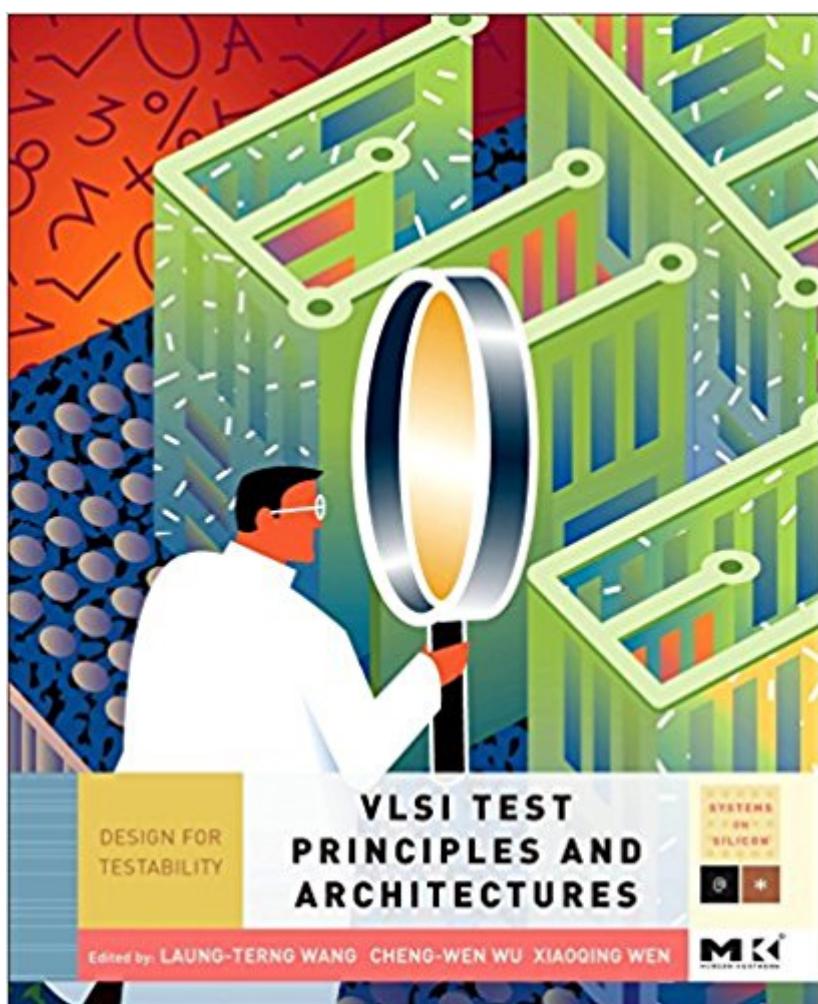


The book was found

VLSI Test Principles And Architectures: Design For Testability (The Morgan Kaufmann Series In Systems On Silicon)



Synopsis

This book is a comprehensive guide to new DFT methods that will show the readers how to design a testable and quality product, drive down test cost, improve product quality and yield, and speed up time-to-market and time-to-volume. Most up-to-date coverage of design for testability. Coverage of industry practices commonly found in commercial DFT tools but not discussed in other books. Numerous, practical examples in each chapter illustrating basic VLSI test principles and DFT architectures.

Book Information

Series: The Morgan Kaufmann Series in Systems on Silicon

Hardcover: 808 pages

Publisher: Morgan Kaufmann; 1 edition (July 21, 2006)

Language: English

ISBN-10: 0123705975

ISBN-13: 978-0123705976

Product Dimensions: 2 x 7.5 x 9.2 inches

Shipping Weight: 4 pounds (View shipping rates and policies)

Average Customer Review: 5.0 out of 5 stars 3 customer reviews

Best Sellers Rank: #662,104 in Books (See Top 100 in Books) #27 in Books > Engineering & Transportation > Engineering > Electrical & Electronics > Circuits > VLSI & ULSI #90 in Books > Computers & Technology > Hardware & DIY > Microprocessors & System Design > Computer Design #92 in Books > Engineering & Transportation > Engineering > Electrical & Electronics > Circuits > Integrated

Customer Reviews

In the era of large systems embedded in a single system-on-chip (SOC) and fabricated continuously shrinking technologies, it is important to ensure correct behavior of the whole system. Electronic design and test engineers of today have to deal with these complex and heterogeneous systems (digital, mixed-signal, memory), but few have the possibility to study the whole field in a detailed and deep way. This book provides an extremely broad knowledge of the discipline, covering the fundamentals in detail, as well as the most recent and advanced concepts. Michel Renovell, Laboratoire d'Informatique, de Robotique et de Microélectronique de Montpellier (LIRMM), Montpellier, France This book combines in a unique way insight into industry practices commonly found in commercial DFT tools but not discussed in textbooks, and a sound treatment of

the future fundamentals. The comprehensive review of future test technology trends, including self-repair, soft error protection, MEMS testing, and RF testing, leads students and researchers to advanced DFT research. Hans-Joachim Wunderlich, University of Stuttgart, GermanyRecent advances in semiconductor manufacturing have made design for testability (DFT) an essential part of nanometer designs. I am pleased to find a DFT textbook of this comprehensiveness that can serve both academic and professional needs. Andre Ivanov, University of British Columbia, Canada This is the most recent book covering all aspects of digital systems testing. It is a "must read" for anyone focused on learning modern test issues, test research, and test practices. Kewal K. Saluja, University of Wisconsin-MadisonBy covering the basic DFT theory and methodology on digital, memory, as well as analog and mixed-signal (AMS) testing, this book stands out as one best reference book that equips practitioners with testable SOC design skills. Yih Sun, Tsinghua University, Beijing, China

The most up-to-date coverage available of VLSI Testing and Design-for-Testability!

I co-authored a chapter, so I am biased. But I use this book in my graduate test class. It is an excellent text for covering all of the fundamentals of integrated circuit testing - basic design-for-test, and algorithms for test generation and fault simulation.

I have been reading this book for my new role as a DFT Engineer. I must say the concept in this book are very practical. I have been using this book as a reference book along side the requirements of the chip and it has been an invaluable resource. I will definitely recommend this book to anyone trying to understand DFT principles or use it as a reference as part of DFT engineer role. Cheers...

This is a great book for Test/DFT engineers and EDA engineers developing test tool. It gives a thorough review of lot of concepts and techniques employed in practice which cannot be found if you look at a general testing book. This also makes it an excellent resource to prepare for interviews.

[Download to continue reading...](#)

VLSI Test Principles and Architectures: Design for Testability (The Morgan Kaufmann Series in Systems on Silicon) Computer Organization and Design MIPS Edition, Fifth Edition: The Hardware/Software Interface (The Morgan Kaufmann Series in Computer Architecture and Design)

Self-Checking and Fault-Tolerant Digital Design (The Morgan Kaufmann Series in Computer Architecture and Design) Computer Organization and Design, Fourth Edition: The Hardware/Software Interface (The Morgan Kaufmann Series in Computer Architecture and Design) Skew-Tolerant Circuit Design (The Morgan Kaufmann Series in Computer Architecture and Design) Data Mining: Practical Machine Learning Tools and Techniques (Morgan Kaufmann Series in Data Management Systems) Data Mining: Concepts and Techniques, Third Edition (The Morgan Kaufmann Series in Data Management Systems) Data Mining, Fourth Edition: Practical Machine Learning Tools and Techniques (Morgan Kaufmann Series in Data Management Systems) Data Mining: Practical Machine Learning Tools and Techniques, Third Edition (Morgan Kaufmann Series in Data Management Systems) Data Mining: Practical Machine Learning Tools and Techniques, Second Edition (Morgan Kaufmann Series in Data Management Systems) Computer Networks, Fifth Edition: A Systems Approach (The Morgan Kaufmann Series in Networking) Computer Networks: A Systems Approach (The Morgan Kaufmann Series in Networking) VLSI DESIGN SIMPLE AND LUCID EXPLANATION: vlsi design for students Foundations of Analog and Digital Electronic Circuits (The Morgan Kaufmann Series in Computer Architecture and Design) Logical Effort: Designing Fast CMOS Circuits (The Morgan Kaufmann Series in Computer Architecture and Design) See MIPS Run, Second Edition (The Morgan Kaufmann Series in Computer Architecture and Design) Circuits, Interconnections, and Packaging for Vlsi (Addison-Wesley VLSI systems series) Game Feel: A Game Designer's Guide to Virtual Sensation (Morgan Kaufmann Game Design Books) Algorithms, Complexity Analysis and VLSI Architectures for MPEG-4 Motion Estimation VLSI Fabrication Principles: Silicon and Gallium Arsenide, 2nd Edition

[Contact Us](#)

[DMCA](#)

[Privacy](#)

[FAQ & Help](#)